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Product Affected:			
INA138QPWRQ1	INA168QDBVRQ1	INA168QPWRG4Q1	INA168QPWRQ1

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
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Europe	PCNEuropeContact@list.ti.com
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